

<b>Notice of References Cited</b>	Application/Control No. <b>10/045,273</b>	Applicant(s)/Patent Under Reexam <b>Mako et al.</b>
	Examiner <b>Robert H. Spitzer</b>	Art Unit <b>1724</b>

**U.S. PATENT DOCUMENTS**

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY <sup>1</sup>	Name	Classification <sup>2</sup>	
x A	4,312,640	1/1982	Verrando	95	105
x B	4,312,641	1/1982	Verrando et al.	95	105
x C	5,087,272	2/1992	Nixdorf	95	278X
x D	5,180,559	1/1993	Ma	55	DIG. 30
x E	5,194,078	3/1993	Yonemura et al.	55	DIG. 30
x F	5,195,317	3/1993	Nobue et al.	55	DIG. 30
x G	5,429,665	7/1995	Botich	95	122X
H					
I					
J					
K					
L					
M					

**FOREIGN PATENT DOCUMENTS**

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY <sup>1</sup>	Country	Name	Classification <sup>2</sup>	
x N	0,327,439	8/1989	EPO	-----	55	DIG. 10
x O	4,014,153	12/1991	Germany	-----	55	DIG. 10
x P	62-277,125	12/1987	Japan	-----	95	122
x Q	63-065,920	12/1988	Japan	-----	95	278
x R	02-203,913	8/1990	Japan	-----	95	278
x S	04-012,113	1/1992	Japan	-----	55	DIG. 10
T						

**NON-PATENT DOCUMENTS**

*	Include, as applicable: Author, Title, Date, Publisher, Edition or Volume, Pertinent Pages	
U		
V		
W		
X		

<sup>1</sup> A copy of this reference is not being furnished with this Office action. See MPEP § 707.05(a).

<sup>1</sup> Dates in MM-YYYY format are publication dates.

<sup>2</sup> Classifications may be U.S. or foreign.